

| | | | | |
|-----------------------------------|---------------------------------------|--|---|-------------|
| Notice of References Cited | Application/Control No. 10/554,235 | | Applicant(s)/Patent Under Reexamination TANI ET AL. | |
| | Examiner PATRICIA L. HAILEY | | Art Unit 1793 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-5,069,885 A | 12-1991 | Ritchie, David G. | 422/186 |
| * | B | US-5,262,199 A | 11-1993 | Desu et al. | 427/255.32 |
| * | C | US-5,516,492 A | 05-1996 | Dong et al. | 422/186 |
| * | D | US-6,238,631 B1 | 05-2001 | Ogata et al. | 422/186.3 |
| * | E | US-2005/0084717 A1 | 04-2005 | Tani et al. | 428/698 |
| * | F | US-2005/0209088 A1 | 09-2005 | Tani, Elji | 501/080 |
| * | G | US-2006/0269683 A1 | 11-2006 | Tani, Eiji | 427/430.1 |
| * | H | US-2009/0162567 A1 | 06-2009 | TSENG et al. | 427/541 |
| * | I | US-6,673,738 | 01-2004 | Ueda et al. | 502/180 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|-------------|----------------|
| | N | 11-128631 | 05-1999 | Japan | Ogawa | B01D 39/14 |
| | O | 1 656 985 | 05-2006 | Europe | Tani et al. | B01D 53/86 |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.